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Applications of "<u>Embedded -</u> <u>Microcontrollers</u>"

Details

E·XFl

Product Status	Obsolete
Core Processor	C166SV2
Core Size	16-Bit
Speed	80MHz
Connectivity	EBI/EMI, I ² C, LINbus, SPI, SSC, UART/USART, USI
Peripherals	I ² S, POR, PWM, WDT
Number of I/O	76
Program Memory Size	384КВ (384К х 8)
Program Memory Type	FLASH
EEPROM Size	
RAM Size	34K x 8
Voltage - Supply (Vcc/Vdd)	3V ~ 5.5V
Data Converters	A/D 11x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	100-LQFP Exposed Pad
Supplier Device Package	PG-LQFP-100-8
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/xe164km48f80laafxuma1

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Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

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Summary of Features

16-Bit Single-Chip Real Time Signal Controller XE164xM (XE166 Family)

1 Summary of Features

For a quick overview and easy reference, the features of the XE164xM are summarized here.

- High-performance CPU with five-stage pipeline and MPU
 - 12.5 ns instruction cycle at 80 MHz CPU clock (single-cycle execution)
 - One-cycle 32-bit addition and subtraction with 40-bit result
 - One-cycle multiplication (16 × 16 bit)
 - Background division (32 / 16 bit) in 21 cycles
 - One-cycle multiply-and-accumulate (MAC) instructions
 - Enhanced Boolean bit manipulation facilities
 - Zero-cycle jump execution
 - Additional instructions to support HLL and operating systems
 - Register-based design with multiple variable register banks
 - Fast context switching support with two additional local register banks
 - 16 Mbytes total linear address space for code and data
 - 1024 Bytes on-chip special function register area (C166 Family compatible)
 - Integrated Memory Protection Unit (MPU)
- Interrupt system with 16 priority levels for up to 96 sources
 - Selectable external inputs for interrupt generation and wake-up
 - Fastest sample-rate 12.5 ns
- Eight-channel interrupt-driven single-cycle data transfer with Peripheral Event Controller (PEC), 24-bit pointers cover total address space
- Clock generation from internal or external clock sources, using on-chip PLL or prescaler
- Hardware CRC-Checker with Programmable Polynomial to Supervise On-Chip Memory Areas
- On-chip memory modules
 - 8 Kbytes on-chip stand-by RAM (SBRAM)
 - 2 Kbytes on-chip dual-port RAM (DPRAM)
 - Up to 16 Kbytes on-chip data SRAM (DSRAM)
 - Up to 32 Kbytes on-chip program/data SRAM (PSRAM)
 - Up to 576 Kbytes on-chip program memory (Flash memory)
 - Memory content protection through Error Correction Code (ECC)
- On-Chip Peripheral Modules
 - Multi-functional general purpose timer unit with 5 timers
 - 16-channel general purpose capture/compare unit (CAPCOM2)



Table	Table 5 Pin Definitions and Functions (cont'd)							
Pin	Symbol	Ctrl.	Туре	Function				
6	P7.0	O0 / I	St/B	Bit 0 of Port 7, General Purpose Input/Output				
	T3OUT	01	St/B	GPT12E Timer T3 Toggle Latch Output				
	T6OUT	O2	St/B	GPT12E Timer T6 Toggle Latch Output				
	TDO_A	OH / IH	St/B	JTAG Test Data Output / DAP1 Input/Output If DAP pos. 0 or 2 is selected during start-up, an internal pull-down device will hold this pin low when nothing is driving it.				
	ESR2_1	I	St/B	ESR2 Trigger Input 1				
7	P7.3	O0 / I	St/B	Bit 3 of Port 7, General Purpose Input/Output				
	EMUX1	01	St/B	External Analog MUX Control Output 1 (ADC1)				
	U0C1_DOUT	02	St/B	USIC0 Channel 1 Shift Data Output				
	U0C0_DOUT	O3	St/B	USIC0 Channel 0 Shift Data Output				
	CCU62_CCP OS1A	I	St/B	CCU62 Position Input 1				
	TMS_C	IH	St/B	JTAG Test Mode Selection Input If JTAG pos. C is selected during start-up, an internal pull-up device will hold this pin low when nothing is driving it.				
	U0C1_DX0F	I	St/B	USIC0 Channel 1 Shift Data Input				
8	P7.1	O0 / I	St/B	Bit 1 of Port 7, General Purpose Input/Output				
	EXTCLK	O1	St/B	Programmable Clock Signal Output				
	CCU62_CTR APA	I	St/B	CCU62 Emergency Trap Input				
	BRKIN_C	I	St/B	OCDS Break Signal Input				



Table	Table 5 Pin Definitions and Functions (cont'd)							
Pin	Symbol	Ctrl.	Туре	Function				
70	P10.5	O0 / I	St/B	Bit 5 of Port 10, General Purpose Input/Output				
	U0C1_SCLK OUT	O1	St/B	USIC0 Channel 1 Shift Clock Output				
	CCU60_COU T62	O2	St/B	CCU60 Channel 2 Output				
	U2C0_DOUT	O3	St/B	USIC2 Channel 0 Shift Data Output				
	AD5	OH / IH	St/B	External Bus Interface Address/Data Line 5				
	U0C1_DX1B	I	St/B	USIC0 Channel 1 Shift Clock Input				
71	P0.6	O0 / I	St/B	Bit 6 of Port 0, General Purpose Input/Output				
	U1C1_DOUT	01	St/B	USIC1 Channel 1 Shift Data Output				
	TxDC1	O2	St/B	CAN Node 1 Transmit Data Output				
	CCU61_COU T63	O3	St/B	CCU61 Channel 3 Output				
	A6	ОН	St/B	External Bus Interface Address Line 6				
	U1C1_DX0A	I	St/B	USIC1 Channel 1 Shift Data Input				
	CCU61_CTR APA	1	St/B	CCU61 Emergency Trap Input				
	U1C1_DX1B	I	St/B	USIC1 Channel 1 Shift Clock Input				
72	P10.6	O0 / I	St/B	Bit 6 of Port 10, General Purpose Input/Output				
	U0C0_DOUT	O1	St/B	USIC0 Channel 0 Shift Data Output				
	U1C0_SELO 0	O3	St/B	USIC1 Channel 0 Select/Control 0 Output				
	AD6	OH / IH	St/B	External Bus Interface Address/Data Line 6				
	U0C0_DX0C	I	St/B	USIC0 Channel 0 Shift Data Input				
	U1C0_DX2D	I	St/B	USIC1 Channel 0 Shift Control Input				
	CCU60_CTR APA	1	St/B	CCU60 Emergency Trap Input				



XE164FM, XE164GM, XE164HM, XE164KM XE166 Family / Base Line

Table 5 Pin Definitions and Functions (cont'd)								
Pin	Symbol	Ctrl.	Туре	Function				
73	P10.7	O0 / I	St/B	Bit 7 of Port 10, General Purpose Input/Output				
	U0C1_DOUT	01	St/B	USIC0 Channel 1 Shift Data Output				
	CCU60_COU T63	O2	St/B	CCU60 Channel 3 Output				
	AD7	OH / IH	St/B	External Bus Interface Address/Data Line 7				
	U0C1_DX0B	I	St/B	USIC0 Channel 1 Shift Data Input				
	CCU60_CCP OS0A	I	St/B	CCU60 Position Input 0				
	T4INB	I	St/B	GPT12E Timer T4 Count/Gate Input				
74	P0.7	O0 / I	St/B	Bit 7 of Port 0, General Purpose Input/Output				
	U1C1_DOUT	01	St/B	USIC1 Channel 1 Shift Data Output				
	U1C0_SELO 3	O2	St/B	USIC1 Channel 0 Select/Control 3 Output				
	TxDC3	O3	St/B	CAN Node 3 Transmit Data Output				
	A7	ОН	St/B	External Bus Interface Address Line 7				
	U1C1_DX0B	I	St/B	USIC1 Channel 1 Shift Data Input				
	CCU61_CTR APB	1	St/B	CCU61 Emergency Trap Input				
78	P1.0	O0 / I	St/B	Bit 0 of Port 1, General Purpose Input/Output				
	U1C0_MCLK OUT	O1	St/B	USIC1 Channel 0 Master Clock Output				
	U1C0_SELO 4	O2	St/B	USIC1 Channel 0 Select/Control 4 Output				
	A8	ОН	St/B	External Bus Interface Address Line 8				
	ESR1_3	I	St/B	ESR1 Trigger Input 3				
	CCU62_CTR APB	I	St/B	CCU62 Emergency Trap Input				
	T6INB	I	St/B	GPT12E Timer T6 Count/Gate Input				



Table	Table 5 Pin Definitions and Functions (cont'd)							
Pin	Symbol	Ctrl.	Туре	Function				
84	P1.2	O0 / I	St/B	Bit 2 of Port 1, General Purpose Input/Output				
	CCU62_CC6 2	O1	St/B	CCU62 Channel 2 Output				
	U1C0_SELO 6	O2	St/B	USIC1 Channel 0 Select/Control 6 Output				
	U2C1_SCLK OUT	O3	St/B	USIC2 Channel 1 Shift Clock Output				
	A10	ОН	St/B	External Bus Interface Address Line 10				
	ESR1_4	I	St/B	ESR1 Trigger Input 4				
	CCU61_T12 HRB	I	St/B	External Run Control Input for T12 of CCU61				
-	CCU62_CC6 2INA	I	St/B	CCU62 Channel 2 Input				
	U2C1_DX0D	I	St/B	USIC2 Channel 1 Shift Data Input				
	U2C1_DX1C	I	St/B	USIC2 Channel 1 Shift Clock Input				
85	P10.12	O0 / I	St/B	Bit 12 of Port 10, General Purpose Input/Output				
	U1C0_DOUT	01	St/B	USIC1 Channel 0 Shift Data Output				
	TxDC2	02	St/B	CAN Node 2 Transmit Data Output				
	TDO_B	OH / IH	St/B	JTAG Test Data Output / DAP1 Input/Output If DAP pos. 1 is selected during start-up, an internal pull-down device will hold this pin low when nothing is driving it.				
	AD12	OH / IH	St/B	External Bus Interface Address/Data Line 12				
	U1C0_DX0C	I	St/B	USIC1 Channel 0 Shift Data Input				
	U1C0_DX1E	I	St/B	USIC1 Channel 0 Shift Clock Input				



Table 5 Pin Definitions and Functions (cont'd)							
Pin	Symbol	Ctrl.	Туре	Function			
93	P1.6	O0 / I	St/B	Bit 6 of Port 1, General Purpose Input/Output			
	CCU62_CC6 1	O1 / I	St/B	CCU62 Channel 1 Output			
	U1C1_SELO 2	O2	St/B	USIC1 Channel 1 Select/Control 2 Output			
	U2C0_DOUT	O3	St/B	USIC2 Channel 0 Shift Data Output			
	A14	ОН	St/B	External Bus Interface Address Line 14			
	U2C0_DX0D	I	St/B	USIC2 Channel 0 Shift Data Input			
	CCU62_CC6 1INA	I	St/B	CCU62 Channel 1 Input			
94	P1.7	O0 / I	St/B	Bit 7 of Port 1, General Purpose Input/Output			
	CCU62_CC6 0	O1	St/B	CCU62 Channel 0 Output			
	U1C1_MCLK OUT	O2	St/B	USIC1 Channel 1 Master Clock Output			
	U2C0_SCLK OUT	O3	St/B	USIC2 Channel 0 Shift Clock Output			
	A15	ОН	St/B	External Bus Interface Address Line 15			
	U2C0_DX1C	I	St/B	USIC2 Channel 0 Shift Clock Input			
	CCU62_CC6 0INA	I	St/B	CCU62 Channel 0 Input			
95	XTAL2	0	Sp/M	Crystal Oscillator Amplifier Output			
96	XTAL1	I	Sp/M	Crystal Oscillator Amplifier Input To clock the device from an external source, drive XTAL1, while leaving XTAL2 unconnected. Voltages on XTAL1 must comply to the core supply voltage V_{DDIM} .			
	ESR2_9	I	St/B	ESR2 Trigger Input 9			



Functional Description

3.2 External Bus Controller

All external memory access operations are performed by a special on-chip External Bus Controller (EBC). The EBC also controls access to resources connected to the on-chip LXBus (MultiCAN and the USIC modules). The LXBus is an internal representation of the external bus that allows access to integrated peripherals and modules in the same way as to external components.

The EBC can be programmed either to Single Chip Mode, when no external memory is required, or to an external bus mode with the following selections¹):

- Address Bus Width with a range of 0 ... 24-bit
- Data Bus Width 8-bit or 16-bit
- Bus Operation Multiplexed or Demultiplexed

The bus interface uses Port 10 and Port 2 for addresses and data. In the demultiplexed bus modes, the lower addresses are output separately on Port 0 and Port 1. The number of active segment address lines is selectable, restricting the external address space to 8 Mbytes ... 64 Kbytes. This is required when interface lines shall be assigned to Port 2.

External \overline{CS} signals (address windows plus default) can be generated and output on Port 4 in order to save external glue logic. External modules can be directly connected to the common address/data bus and their individual select lines.

Important timing characteristics of the external bus interface are programmable (with registers TCONCSx/FCONCSx) to allow the user to adapt it to a wide range of different types of memories and external peripherals.

Access to very slow memories or modules with varying access times is supported by a special 'Ready' function. The active level of the control input signal is selectable.

In addition, up to four independent address windows may be defined (using registers ADDRSELx) to control access to resources with different bus characteristics. These address windows are arranged hierarchically where window 4 overrides window 3, and window 2 overrides window 1. All accesses to locations not covered by these four address windows are controlled by TCONCS0/FCONCS0. The currently active window can generate a chip select signal.

The external bus timing is based on the rising edge of the reference clock output CLKOUT. The external bus protocol is compatible with that of the standard C166 Family.

¹⁾ Bus modes are switched dynamically if several address windows with different mode settings are used.



Functional Description

3.14 MultiCAN Module

The MultiCAN module contains independently operating CAN nodes with Full-CAN functionality which are able to exchange Data and Remote Frames using a gateway function. Transmission and reception of CAN frames is handled in accordance with CAN specification V2.0 B (active). Each CAN node can receive and transmit standard frames with 11-bit identifiers as well as extended frames with 29-bit identifiers.

All CAN nodes share a common set of message objects. Each message object can be individually allocated to one of the CAN nodes. Besides serving as a storage container for incoming and outgoing frames, message objects can be combined to build gateways between the CAN nodes or to set up a FIFO buffer.

Note: The number of CAN nodes and message objects depends on the selected device type.

The message objects are organized in double-chained linked lists, where each CAN node has its own list of message objects. A CAN node stores frames only into message objects that are allocated to its own message object list and it transmits only messages belonging to this message object list. A powerful, command-driven list controller performs all message object list operations.

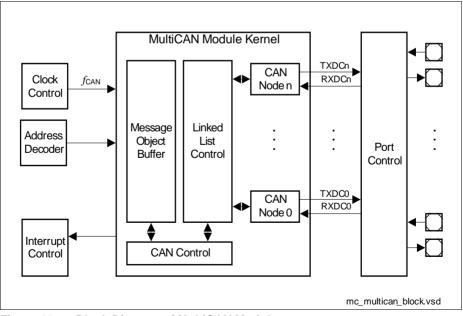


Figure 12 Block Diagram of MultiCAN Module



Functional Description

Table 10 Instruction Set Summary (cont'd)						
Mnemonic	Description	Bytes				
NOP	Null operation	2				
CoMUL/CoMAC	Multiply (and accumulate)	4				
CoADD/CoSUB	Add/Subtract	4				
Co(A)SHR	(Arithmetic) Shift right	4				
CoSHL	Shift left	4				
CoLOAD/STORE	Load accumulator/Store MAC register	4				
CoCMP	Compare	4				
CoMAX/MIN	Maximum/Minimum	4				
CoABS/CoRND	Absolute value/Round accumulator	4				
CoMOV	Data move	4				
CoNEG/NOP	Negate accumulator/Null operation	4				

1) The Enter Power Down Mode instruction is not used in the XE164xM, due to the enhanced power control scheme. PWRDN will be correctly decoded, but will trigger no action.



4.2 DC Parameters

These parameters are static or average values that may be exceeded during switching transitions (e.g. output current).

Leakage current is strongly dependent on the operating temperature and the voltage level at the respective pin. The maximum values in the following tables apply under worst case conditions, i.e. maximum temperature and an input level equal to the supply voltage.

The value for the leakage current in an application can be determined by using the respective leakage derating formula (see tables) with values from that application.

The pads of the XE164xM are designed to operate in various driver modes. The DC parameter specifications refer to the pad current limits specified in **Section 4.6.4**.

Supply Voltage Restrictions

The XE164xM can operate within a wide supply voltage range from 3.0 V to 5.5 V. However, during operation this supply voltage must remain within 10 percent of the selected nominal supply voltage. It cannot vary across the full operating voltage range.

Because of the supply voltage restriction and because electrical behavior depends on the supply voltage, the parameters are specified separately for the upper and the lower voltage range.

During operation, the supply voltages may only change with a maximum speed of dV/dt < 1 V/ms.

During power-on sequences, the supply voltages may only change with a maximum speed of dV/dt < 5 V/ μ s, i.e. the target supply voltage may be reached earliest after approx. 1 μ s.

Note: To limit the speed of supply voltage changes, the employment of external buffer capacitors at pins V_{DDPA}/V_{DDPB} is recommended.



4.2.1 DC Parameters

Keeping signal levels within the limits specified in this table ensures operation without overload conditions. For signal levels outside these specifications, also refer to the specification of the overload current I_{OV} .

Note: Operating Conditions apply.

 Table 13 is valid under the following conditions:

 $V_{\text{DDP}} \ge 4.5 \text{ V}; V_{\text{DDPtvp}} = 5 \text{ V}; V_{\text{DDP}} \le 5.5 \text{ V}$

Parameter	Symbol		Values	;	Unit	Note /
		Min. Typ. Max.			Test Condition	
Pin capacitance (digital inputs/outputs). To be doubled for double bond pins. ¹⁾	C _{IO} CC	_	-	10	pF	not subject to production test
Input Hysteresis ²⁾	HYS CC	0.11 x V_{DDP}	_	-	V	$R_{\rm S}$ = 0 Ohm
Absolute input leakage current on pins of analog ports ³⁾	I _{OZ1} CC	-	10	200	nA	$V_{\rm IN} > 0 \ {\rm V}; \\ V_{\rm IN} < V_{\rm DDP}$
Absolute input leakage current for all other pins. To be doubled for double	I _{OZ2} CC	-	0.2	5	μA	$T_{\rm J} \leq 110 ~^{\circ}{\rm C};$ $V_{\rm IN} < V_{\rm DDP};$ $V_{\rm IN} > V_{\rm SS}$
bond pins. ³⁾¹⁾⁴⁾		-	0.2	15	μA	$\begin{array}{l} T_{\rm J} \leq 150 ~^{\circ}{\rm C}; \\ V_{\rm IN} < V_{\rm DDP}; \\ V_{\rm IN} > V_{\rm SS} \end{array}$
Pull Level Force Current ⁵⁾	$ I_{PLF} $ SR	250	-	-	μA	6)
Pull Level Keep Current ⁷⁾	I _{PLK} SR	-	-	30	μA	6)
Input high voltage (all except XTAL1)	$V_{\rm IH}{ m SR}$	$0.7 ext{ x}$ $V_{ ext{DDP}}$	-	V _{DDP} + 0.3	V	
Input low voltage (all except XTAL1)	$V_{IL} SR$	-0.3	-	$0.3 ext{ x}$ $V_{ ext{DDP}}$	V	
Output High voltage ⁸⁾	V _{OH} CC	V _{DDP} - 1.0	_	-	V	$I_{\rm OH} \ge I_{\rm OHmax}$
		V _{DDP} - 0.4	-	-	V	$I_{\rm OH} \ge I_{\rm OHnom}^{9)}$

Table 13 DC Characteristics for Upper Voltage Range



Electrical Parameters

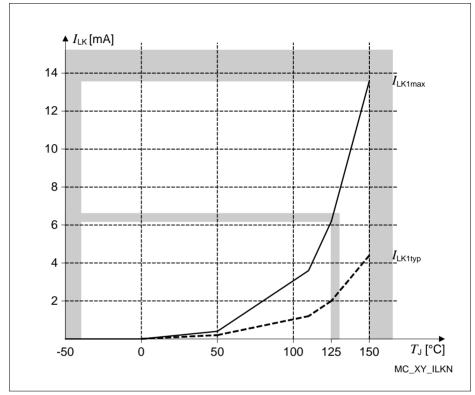


Figure 15 Leakage Supply Current as a Function of Temperature



The timing in the AC Characteristics refers to TCSs. Timing must be calculated using the minimum TCS possible under the given circumstances.

The actual minimum value for TCS depends on the jitter of the PLL. Because the PLL is constantly adjusting its output frequency to correspond to the input frequency (from crystal or oscillator), the accumulated jitter is limited. This means that the relative deviation for periods of more than one TCS is lower than for a single TCS (see formulas and Figure 20).

This is especially important for bus cycles using waitstates and for the operation of timers, serial interfaces, etc. For all slower operations and longer periods (e.g. pulse train generation or measurement, lower baudrates, etc.) the deviation caused by the PLL jitter is negligible.

The value of the accumulated PLL jitter depends on the number of consecutive VCO output cycles within the respective timeframe. The VCO output clock is divided by the output prescaler K2 to generate the system clock signal f_{SYS} . The number of VCO cycles is K2 × **T**, where **T** is the number of consecutive f_{SYS} cycles (TCS).

The maximum accumulated jitter (long-term jitter) D_{Tmax} is defined by:

 D_{Tmax} [ns] = ±(220 / (K2 × f_{SYS}) + 4.3)

This maximum value is applicable, if either the number of clock cycles T > (f_{SYS} / 1.2) or the prescaler value K2 > 17.

In all other cases for a timeframe of $\mathbf{T} \times TCS$ the accumulated jitter D_T is determined by:

 D_{T} [ns] = $D_{Tmax} \times [(1 - 0.058 \times K2) \times (T - 1) / (0.83 \times f_{SYS} - 1) + 0.058 \times K2]$

 f_{SYS} in [MHz] in all formulas.

Example, for a period of 3 TCSs @ 33 MHz and K2 = 4:

 D_{max} = $\pm(220$ / (4 \times 33) + 4.3) = 5.97 ns (Not applicable directly in this case!)

 $D_3 = 5.97 \times [(1 - 0.058 \times 4) \times (3 - 1) / (0.83 \times 33 - 1) + 0.058 \times 4]$

= 5.97 × [0.768 × 2 / 26.39 + 0.232]

Example, for a period of 3 TCSs @ 33 MHz and K2 = 2:

 $D_{max} = \pm (220 / (2 \times 33) + 4.3) = 7.63$ ns (Not applicable directly in this case!)

 $\begin{array}{l} \mathsf{D}_3 = 7.63 \times [(1 - 0.058 \times 2) \times (3 - 1) \ / \ (0.83 \times 33 - 1) + 0.058 \times 2] \\ = 7.63 \times [0.884 \times 2 \ / \ 26.39 + 0.116] \end{array}$



PLL frequency band selection

Different frequency bands can be selected for the VCO so that the operation of the PLL can be adjusted to a wide range of input and output frequencies:

Parameter	Symbol		Values	5	Unit	Note /
		Min.	Тур.	Max.		Test Condition
VCO output frequency	$f_{\rm VCO}{\rm CC}$	50	-	110	MHz	$VCOSEL = 00_B$
(VCO controlled)		100	_	160	MHz	$VCOSEL = 01_B$
VCO output frequency	$f_{\rm VCO}{\rm CC}$	10	-	40	MHz	$VCOSEL = 00_B$
(VCO free-running)		20	-	80	MHz	$VCOSEL = 01_B$

Table 23 System PLL Parameters

4.6.2.2 Wakeup Clock

When wakeup operation is selected (SYSCON0.CLKSEL = 00_B), the system clock is derived from the low-frequency wakeup clock source:

 $f_{SYS} = f_{WU}$.

In this mode, a basic functionality can be maintained without requiring an external clock source and while minimizing the power consumption.

4.6.2.3 Selecting and Changing the Operating Frequency

When selecting a clock source and the clock generation method, the required parameters must be carefully written to the respective bit fields, to avoid unintended intermediate states.

Many applications change the frequency of the system clock (f_{SYS}) during operation in order to optimize system performance and power consumption. Changing the operating frequency also changes the switching currents, which influences the power supply.

To ensure proper operation of the on-chip EVRs while they generate the core voltage, the operating frequency shall only be changed in certain steps. This prevents overshoots and undershoots of the supply voltage.

To avoid the indicated problems, recommended sequences are provided which ensure the intended operation of the clock system interacting with the power system. Please refer to the Programmer's Guide.



4.6.5 External Bus Timing

The following parameters specify the behavior of the XE164xM bus interface.

Note: These parameters are not subject to production test but verified by design and/or characterization.

Note: Operating Conditions apply.

Bus Interface Performance Limits

The output frequency at the bus interface pins is limited by the performance of the output drivers. The fast clock driver (used for CLKOUT) can drive 80-MHz signals, the standard drivers can drive 40-MHz signals

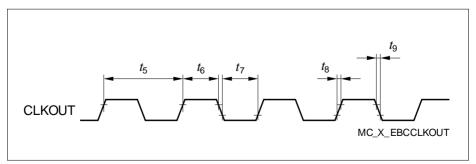
Therefore, the speed of the EBC must be limited, either by limiting the system frequency to $f_{SYS} \le 80$ MHz or by adding waitstates so that signal transitions have a minimum distance of 12.5 ns.

For a description of the bus protocol and the programming of its variable timing parameters, please refer to the User's Manual.

Parameter	Symbol	Values			Unit	Note /
		Min.	Тур.	Max.		Test Condition
CLKOUT Cycle Time ¹⁾	t ₅ CC	-	$1/f_{\rm SYS}$	-	ns	
CLKOUT high time	t ₆ CC	2	-	-		
CLKOUT low time	t ₇ CC	2	-	-		
CLKOUT rise time	t ₈ CC	-	-	3	ns	
CLKOUT fall time	t ₉ CC	-	-	3		

Table 27 EBC Parameters

 The CLKOUT cycle time is influenced by PLL jitter. For longer periods the relative deviation decreases (see PLL deviation formula).







4.6.6 Synchronous Serial Interface Timing

The following parameters are applicable for a USIC channel operated in SSC mode.

Note: These parameters are not subject to production test but verified by design and/or characterization.

Note: Operating Conditions apply; $C_L = 20 \text{ pF}$.

Parameter Symbol Values Unit Note / Test Condition Min. Typ. Max. Slave select output SELO t₁ CC ns t_{SYS} - 8 ¹⁾ active to first SCLKOUT transmit edge Slave select output SELO $t_2 CC$ _ t_{SYS} - 6¹⁾ _ ns inactive after last SCLKOUT receive edge Data output DOUT valid t_3 CC -6 _ 9 ns time Receive data input setup t_4 SR 31 _ _ ns time to SCLKOUT receive edge Data input DX0 hold time t_5 SR -4 ns _ _ from SCLKOUT receive edae

Table 31 USIC SSC Master Mode Timing for Upper Voltage Range

1) $t_{SYS} = 1 / f_{SYS}$

Table 32	USIC SSC Master Mode Timing for Lower Voltage Range
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Parameter	Symbol		Values		Unit	Note /
		Min.	Тур.	Max.		Test Condition
Slave select output SELO active to first SCLKOUT transmit edge	t ₁ CC	<i>t</i> _{SYS} - 10 ¹⁾	_	_	ns	
Slave select output SELO inactive after last SCLKOUT receive edge	t ₂ CC	t _{SYS} - 9 ¹⁾	-	-	ns	
Data output DOUT valid time	t ₃ CC	-7	-	11	ns	



Parameter	Symbol	Values			Unit	Note /
		Min.	Тур.	Max.		Test Condition
DAP0 clock period	<i>t</i> ₁₁ SR	25 ¹⁾	-	-	ns	
DAP0 high time	t ₁₂ SR	8	-	-	ns	
DAP0 low time	t ₁₃ SR	8	-	-	ns	
DAP0 clock rise time	<i>t</i> ₁₄ SR	-	-	4	ns	
DAP0 clock fall time	t ₁₅ SR	-	-	4	ns	
DAP1 setup to DAP0 rising edge	<i>t</i> ₁₆ SR	6	-	-	ns	pad_type= stan dard
DAP1 hold after DAP0 rising edge	<i>t</i> ₁₇ SR	6	-	-	ns	pad_type= stan dard
DAP1 valid per DAP0 clock period ²⁾	<i>t</i> ₁₉ CC	12	17	-	ns	pad_type= stan dard

Table 36 DAP Interface Timing for Lower Voltage Range

1) The debug interface cannot operate faster than the overall system, therefore $t_{11} \ge t_{SYS}$.

2) The Host has to find a suitable sampling point by analyzing the sync telegram response.

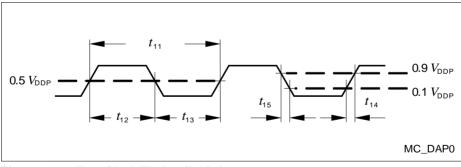


Figure 27 Test Clock Timing (DAP0)



Package and Reliability

5 Package and Reliability

The XE166 Family devices use the package type PG-LQFP (Plastic Green - Low Profile Quad Flat Package). The following specifications must be regarded to ensure proper integration of the XE164xM in its target environment.

5.1 Packaging

These parameters specify the packaging rather than the silicon.

Parameter	Symbol	Lin	nit Values	Unit	Notes
		Min.	Max.		
Exposed Pad Dimension	$E x \times E y$	-	6.2 × 6.2	mm	-
Power Dissipation	P _{DISS}	-	1.0	W	-
Thermal resistance Junction-Ambient	R _{OJA}	-	47	K/W	No thermal via ¹⁾
			29	K/W	4-layer, no pad ²⁾
			23	K/W	4-layer, pad ³⁾

 Table 39
 Package Parameters (PG-LQFP-100-8)

1) Device mounted on a 2-layer JEDEC board (according to JESD 51-3) or a 4-layer board without thermal vias; exposed pad not soldered.

 Device mounted on a 4-layer JEDEC board (according to JESD 51-7) with thermal vias; exposed pad not soldered.

 Device mounted on a 4-layer JEDEC board (according to JESD 51-7) with thermal vias; exposed pad soldered to the board.

Note: To improve the EMC behavior, it is recommended to connect the exposed pad to the board ground, independent of the thermal requirements. Board layout examples are given in an application note.

Package Compatibility Considerations

The XE164xM is a member of the XE166 Family of microcontrollers. It is also compatible to a certain extent with members of similar families or subfamilies.

Each package is optimized for the device it houses. Therefore, there may be slight differences between packages of the same pin-count but for different device types. In particular, the size of the Exposed Pad (if present) may vary.

If different device types are considered or planned for an application, it must be ensured that the board layout fits all packages under consideration.

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